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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/720,839	11/24/2003	Robert J. Steger	LMRX-P028/P1187	3615
32986	7590	12/15/2004	EXAMINER	
IPSG, P.C. P.O. BOX 700640 SAN JOSE, CA 95170-0640				PRUCHNIC, STANLEY J
			ART UNIT	PAPER NUMBER
			2859	

DATE MAILED: 12/15/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

AK

<b>Office Action Summary</b>	Application No.	Applicant(s)
	10/720,839	STEGER, ROBERT J.
	Examiner	Art Unit
	Stanley J. Pruchnic, Jr.	2859

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --  
**Period for Reply**

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM  
 THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

#### Status

- 1) Responsive to communication(s) filed on \_\_\_\_\_.
- 2a) This action is **FINAL**.                    2b) This action is non-final.
- 3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

#### Disposition of Claims

- 4) Claim(s) 1-49 is/are pending in the application.
- 4a) Of the above claim(s) \_\_\_\_\_ is/are withdrawn from consideration.
- 5) Claim(s) 49 is/are allowed.
- 6) Claim(s) 1-48 is/are rejected.
- 7) Claim(s) \_\_\_\_\_ is/are objected to.
- 8) Claim(s) \_\_\_\_\_ are subject to restriction and/or election requirement.

#### Application Papers

- 9) The specification is objected to by the Examiner.
- 10) The drawing(s) filed on 24 November 2003 is/are: a) accepted or b) objected to by the Examiner.  
 Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).  
 Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

#### Priority under 35 U.S.C. § 119

- 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).  
 a) All    b) Some \* c) None of:  
 1. Certified copies of the priority documents have been received.  
 2. Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.  
 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

\* See the attached detailed Office action for a list of the certified copies not received.

#### Attachment(s)

- 1) Notice of References Cited (PTO-892)
- 2) Notice of Draftsperson's Patent Drawing Review (PTO-948)
- 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)  
 Paper No(s)/Mail Date \_\_\_\_\_
- 4) Interview Summary (PTO-413)  
 Paper No(s)/Mail Date. \_\_\_\_\_
- 5) Notice of Informal Patent Application (PTO-152)
- 6) Other: \_\_\_\_\_

## DETAILED ACTION

### *Claim Objections*

1. Claims 1, 3, 10, 12-15, 25, 27, 34 and 36-39 are objected to because of the following informalities:

- a. In Claim 1, in Line 8, perhaps after the phrase "physical measuring device", insert the phrase -- in thermal contact with said chuck -- in order to more clearly describe the invention.
- b. In Claim 25, in Line 8, perhaps after the phrase "physical measuring device", insert the phrase -- in thermal contact with said chuck -- in order to more clearly describe the invention.
- c. In Claim 1, in Line 8, perhaps after the phrase "during a first isothermal state" the phrase --of said substrate and said chuck, in the absence of a plasma in the system, -- should be inserted in order to more clearly describe the invention by indicating more clearly the portions of the plasma processing system that are in said "first isothermal state" and to clearly indicate that plasma is not affecting the measurements when creating the temperature calibration curve.
- d. In Claim 25, in Line 8, perhaps after the phrase "during a first isothermal state" the phrase --of said substrate and said chuck, in the absence of a plasma in the system, -- should be inserted in order to more clearly describe the invention by indicating more clearly the portions of the plasma processing system that are in said "first isothermal state" and to clearly indicate that plasma is not affecting the measurements when creating the temperature calibration curve.
- e. In Claim 3, in Line 1, "said plasma" lacks antecedent basis.
- f. In Claim 1, in Line 11, perhaps after "plasma processing", insert the phrase --, wherein a plasma is generated in said plasma processing system-- in order to provide antecedent basis for "said plasma" in Claim 3.

- g. In Claim 27, in Lines 1-2, "said plasma" lacks antecedent basis.
- h. In Claim 25, in Line 11, perhaps after "plasma processing", insert the phrase --, wherein a plasma is generated in said plasma processing system-- in order to provide antecedent basis for "said plasma" in Claim 27.
- i. In Claim 10, in Line 1, following "substrate is a", perhaps delete the last word in the claim, "substrate", and replace therefor the phrase -- silicon wafer --in order to more clearly describe the invention, since the claim does not further limit the subject matter of claim 1 as written.
- j. In Claim 34, in Line 1, following "substrate is a", perhaps delete the last word in the claim, "substrate", and replace therefor the phrase -- silicon wafer --in order to more clearly describe the invention, since the claim does not further limit the subject matter of claim 1 as written.
- k. In each of Claims 12 and 36, in Line 1, "said set of electromagnetic frequencies" lacks antecedent basis. Moreover, "comprises" is an "open-ended" form of claim construction, therefore the claim does not exclude electromagnetic frequencies outside of the infrared portion of the spectrum.
- l. In each of claims 13, 14, 15, 37, 38 and 39: "said plasma processing system comprises" is followed by a particular type of processing method, e.g., in Claim 13, "chemical vapor deposition" is a method. This is only modifying how the system is used and, in the apparatus claims, requires the system to be capable of being used to practice the method of "chemical vapor deposition", for example. Perhaps to clarify the grammar, insert --a-- before "chemical vapor deposition" in Claim 13, Line 2, and insert the word --system-- after "chemical vapor deposition". Similarly, the other claims should be corrected.

Appropriate correction is required.

***Claim Rejections - 35 USC § 103***

2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

3. Claims 1-4, 9-11, 13-28, 33-35, 37-48 are rejected under 35 U.S.C. 103(a) as being unpatentable over US 6191399 B1 (Van Bilsen; Frank B. M., herein after VAN BILSEN) in view of US 5225245 A (Ohta; Tomohiro *et al.*, hereinafter OHTA)

With respect to Claims 1 and 25: VAN BILSEN discloses or suggests, in a heated substrate processing system, which may be used for Chemical Vapor Deposition (CVD), a method and apparatus for determining the temperature of a substrate, comprising:

positioning said substrate 16 on a substrate support structure (18, Fig. 1), wherein said substrate support structure includes a chuck (considered to be the wafer holder 20, which is supported by spider 22 mounted to a shaft 24 which extends through a tube 26; Col. 4, Lines 32-37);

creating a temperature calibration curve (Col. 7, Lines 1-67) for said substrate, said temperature calibration curve (e.g., adding an offset to make the pyrometer 21 readings match the thermocouple 28 at the first temperature) being created by measuring at least a first substrate temperature with an electromagnetic measuring device (non-contact temperature sensor 21 such as a pyrometer), and measuring a first wafer temperature with a physical measuring device (thermocouple 28) during a first isothermal state (a stable temperature portion, Tf, Fig. 4); and

employing a measurement from said electromagnetic measurement device and said temperature calibration curve to determine a temperature of said substrate during processing of said substrate.

Regarding Claims 2 and 26: VAN BILSEN further discloses selecting a setpoint and calibrating the pyrometer by measuring the temperature of the substrate using the thermocouple when the setpoint has been reached, and is stable, considered an "isothermal state" of the system, VAN BILSEN refers to as a "steady state portion of the recipe" (Col. 2, Lines 55-65; Col. 7, Lines 17-24).

VAN BILSEN further discloses the support structure further comprises said physical temperature measuring device, as claimed by Applicant in Claims 4 and 28, the physical temperature measuring device is a thermocouple device 28, as claimed by Applicant in Claims 9 and 33.

VAN BILSEN, as described above, does not disclose the method and apparatus being used in a plasma processing system as claimed by Applicant in Claims 1 and 25; and wherein the plasma processing system comprises ***plasma processing*** system(s) for chemical vapor deposition, plasma enhanced chemical vapor deposition, and/or physical vapor deposition as claimed by Applicant in Claims 13-15 and 37-39. Moreover, VAN BILSEN, as described above, does not disclose the method and apparatus wherein said substrate is positioned between said plasma and said electromagnetic device as claimed by Applicant in Claims 3 and 27.

OHTA discloses, in a heated processing system, including a thermocouple 13, and "non-contact type thermometer 9, e.g., a radiation pyrometer", which may be used for Chemical Vapor Deposition (CVD), that the system can be modified to use plasma (Col. 1, Lines 45-68). Moreover, the system can be used for plasma enhanced chemical vapor deposition and physical vapor deposition (Col. 7, Line 24 - Col. 8, Line 6) as claimed by Applicant in Claims 13-15 and 37-39.

OHTA further discloses that it is advantageous to substitute plasma for the filament, as the decomposing means for decomposing the source gas in order to benefit from the ability to make thin films of superior quality.

OHTA is evidence that ordinary workers in the field of thin film manufacturing processes would recognize the benefit of using plasma as taught by OHTA in a CVD reactor using the temperature calibration method of VAN BILSEN in order to benefit from the ability to make thin films of superior quality using plasma.

Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to substitute plasma for decomposing the source gas in the system of OHTA in order to make thin films of superior quality using plasma as taught by OHTA and to use the method of temperature calibration of VAN BILSEN in that system in order to more accurately determine the operating temperature for a CVD recipe as taught by VAN BILSEN.

VAN BILSEN further discloses the wafer/substrate may be a silicon wafer, as Claims 10 and 34 have been considered, as described in Paragraph 1, above, and may be used for other substrates, such as for deposition of optical thin films on glass (Col. 3, Lines 33-50). VAN BILSEN does not explicitly disclose using the method and system for processing wherein said substrate is a glass panel. Official Notice is taken with respect to the intended use in processing a glass panel, since it is well known in the art that glass panels are commonly coated by CVD in order to provide improved optical properties. Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to substitute a glass panel for the substrate of VAN BILSEN in order to apply a coating to the panel providing beneficial optical properties as is well known in the art.

Official Notice is taken with respect to the intended use of the particular processing gases as claimed by Applicant in Claims 13-24 and 37-48, since it is well known in the art that these gases are commonly used for either carrier gases or deposition gases for sputtering, plasma etching as well as deposition processes and Sulfur, Fluorine and Carbon compounds are commonly used for reactive sputtering, which are commonly done in the same plasma processing system as suggested by the teachings of VAN BILSEN in view of OHTA. Therefore, it would have been obvious to

one having ordinary skill in the art at the time the invention was made to use any of these gases for the various well-known processes that are commonly done in plasma reactors, such as surface preparation by sputter cleaning, then applying a coating to the substrate providing the desired properties needed for the manufacture of thin film devices as is well known in the art.

4. Claims 5-8, 12, 29-32 and 36 are rejected under 35 U.S.C. 103(a) as being unpatentable over VAN BILSEN in view OHTA and further in view of US 6062729 A (Ni; Tuqiang *et al.*, hereinafter NI).

BILSEN in view OHTA discloses or suggests all the limitations as claimed by Applicant in Claims 5-8, 12, 29-32 and 36, as described above in Paragraph 3 regarding Claims 1-4, 9-11, 13-28, 33-35, 37-48, including the limitations wherein the electromagnetic measuring device comprises a pyrometer, each generally disclosing a pyrometer for temperature measurement and a radiation pyrometer. Neither BILSEN nor OHTA explicitly disclose the set of electromagnetic frequencies comprising the infrared spectrum as claimed by Applicant in Claims 12 and 36, and neither explicitly disclose the pyrometer being a narrow-band pyrometer as claimed by Applicant in Claims 5 and 29, or comprising the particular spectral discrimination devices as claimed by Applicant in Claims 6-8 and 30-32.

NI discloses that is known in the art to provide a plasma processing system with an infrared responsive technique for measuring substrate temperature (Col. 3, Lines 1-49).

NI further teaches that it is advantageous to use a broadband source including infrared frequencies as claimed by Applicant in Claims 12 and 36, and spectrally

sensitive photodiode 24 in order to benefit from ability to discriminate from light generated by the plasma emissions (Col. 5, Lines 4-32).

NI teaches use of optic filters FA and FB in combination with a pair of photodiodes 26, 28 as claimed by Applicant in Claims 5, 8, 29 and 32. Regarding claims 6-7 and 30-31, the monochrometer and grating are dispersive filters, art-recognized equivalents for band-pass optical filters as is well known in the art of temperature measurement.

NI is evidence that ordinary workers in the field of semiconductor processing device temperature measurements would recognize the benefit of providing a broadband source including infrared frequencies and spectrally sensitive detection as taught by NI for the pyrometers of BILSEN and OHTA in order to discriminate from the plasma generated light wavelengths, in order to more accurately measure the temperature of the substrate in the presence of the plasma.

Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to substitute the temperature measurement of NI for the pyrometer of BILSEN and OHTA in order to more accurately measure the temperature of the substrate in the presence of the plasma as taught by NI.

#### ***Allowable Subject Matter***

5. Claim 49 is allowed.
6. As allowable subject matter has been indicated, applicant's reply must either comply with all formal requirements or specifically traverse each requirement not complied with. See 37 CFR 1.111(b) and MPEP § 707.07(a).

7. The following is a statement of reasons for the indication of allowable subject matter: A closely related prior art patent is 6116779 A (Johnson; Shane R. et al., hereinafter JOHNSON).

JOHNSON discloses, in a plasma processing system (Col. 1, Lines 8-16), a method of determining the temperature of a substrate during plasma processing, comprising:

creating a mathematical model (Col. 8, Lines 1-54; Figs. 3-4; Col. 7, Lines 48-68, and following) relating temperature changes of said substrate to optical properties changes of said substrate (Col. 3, Lines 49-59), including

a) positioning said substrate (wafer 5) on a substrate support structure of said plasma processing system, wherein said substrate support structure includes a chuck (metal ring 8; Col. 5, Lines 10-16), "a thermocouple clipped to the substrate"; Col. 11, Lines 10-45), is considered to be thermally attached to the chuck, with the substrate and said chuck required to come to thermal equilibration, in order to provide accurate measurement of the wafer temperature by way of the chuck temperature, at which time said chuck temperature is measured using a contact measurement technique,

d) directing electromagnetic radiation of known spectral composition (a broadband lamp 1 with long pass filter 16; Col. 5, Lines 31-37; 45-53) onto a surface of said substrate 5,

e) obtaining first electromagnetic energy measurement, said first electromagnetic energy measurement measuring first electromagnetic energy reflected from said surface of said substrate responsive to said directing (Col. 6, Lines 55-68).

JOHNSON as described above, does not teach introducing a heat transfer gas between said substrate and said chuck, allowing said substrate and said chuck to come to thermal equilibration, at which time said chuck temperature is measured using a contact measurement technique; then employing said chuck temperature measured using said contact measurement technique and said first electromagnetic energy measurement to create said mathematical model.

In contrast, during the calibration step, JOHNSON uses a thermocouple in direct thermal contact. JOHNSON recognizes the problem of using a thermocouple close to the wafer without touching, depending only on radiative contact with the substrate for heat transfer, or equilibration (Col. 1, Lines 25-43), which may have errors of 100 degrees Celsius using that approach. He solves this by using the direct contact approach during the calibration step.

Thus, JOHNSON does not anticipate or fairly suggest the step of using the same substrate for both the calibration step and the measuring step during plasma processing, that is, calculating said temperature of said substrate during said plasma processing as claimed by Applicant, in combination with all the other limitations of Claim 49.

### ***Conclusion***

8. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. The prior art cited in a form PTO-892 and not mentioned above disclose related temperature measurement devices and methods.

US 6106148 A (Moslehi; Mehrdad M. et al.), in a plasma processing system, calibrates a pyrometer using a thermocouple, wherein the thermocouple is touched to a wafer during a ramping of temperature of the wafer. There is no measuring a first chuck temperature with a physical measuring device during a first isothermal state. The ramp rate must be slow enough for the thermocouple probe to respond to correlate with the pyrometer response.

US 4854727 A (Pecot; Michel et al.), as described in VAN BILSEN, "discloses an exemplary method for calibrating the emissivity characteristics of a semiconductor wafer temperature measurement element. [Pecot et al.] discloses comparing the temperature measured within a susceptor in close proximity to the center of the wafer with the temperature measured by a radiation pyrometer by using a sample wafer, prior to the processing of a batch of similar wafers. The temperature measurements for the wafers in the batch are corrected with reference to the measurements taken by using the sample wafer." Pecot et al. does not disclose or fairly suggest employing a measurement from said electromagnetic measurement device and said temperature calibration curve to determine a temperature of said substrate during plasma processing.

US 6575622 B2 (Norrbakhsh; Hamid et al.) discloses an electromagnetic measuring device (optical or fluoroptical temperature sensor) including measurements of a test wafer and also physical contact device measuring a wafer support temperature, in order to establish a database for corrections made during temperature measurements during plasma processing. Also discloses use of Helium gas for conducting heat.

US 5823681 A (Cabib; Dario et al.), in a plasma processing system, calibrates an electromagnetic measuring device using a thermocouple 44 embedded in a chuck (heater 46), wherein the thermocouple is used to compensate for the background radiation caused by the heater. Also uses gas to equilibrate the temperature of the heater and the reference wafer.

Art Unit: 2859

The following disclose related temperature calibration and measuring methods:

- US 6283630 B1 (Yazawa; Minoru);
- US 20010014111 A1 (Shimizu, Masahiro).

The following disclose related apparatus:

- US 5021980 A (Poenisch; Paul et al.);
- US 4919542 A (Nulman; Jaim et al.).

9. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Stanley J. Pruchnic, Jr., whose telephone number is **(571) 272-2248**. The examiner can normally be reached on weekdays (Monday through Friday) from 7:30 AM to 4:00 PM. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Diego F. F. Gutierrez can be reached at **(571) 272-2245**.

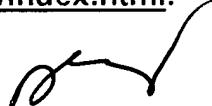
The **Official FAX** number for Technology Center 2800 is **(703) 872-9306** for **all official communications**.

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DIEGO F. F. GUTIERREZ  
SUPERVISORY PATENT EXAMINER  
TECHNOLOGY CENTER 2800

  
Stanley J. Pruchnic, Jr.  
12/11/04